



Reltech

meeting your
demands for
reliability assurance

Reltech Limited... the leading specialist in Burn-In and Life Test System technology for Logic and Mixed Signal semiconductor devices

- ◆ 25 Years experience in Burn-In Reliability Life Testing technology
- ◆ Production high volume burn-in and reliability testing
- ◆ Fully software controlled and monitored reliability test systems
- ◆ Continually exceeding the industry challenge for technological development in test for the very latest device types

Providing the complete solution for Advanced Burn-In and Reliability testing needs

- ◆ High Performance Test Chambers
- ◆ High Speed Dynamic Stimulation
- ◆ MIDAS© (Microprocessor Data Acquisition System) Control and Monitoring system
- ◆ Logic and Mixed Signal device testing capability
- ◆ Easily configured systems providing many options of temperature, power and signal zones
- ◆ Up to 12 Power Zones and 48 Signal Zones per System

The MIDAS© 4500 Series Burn-In Reliability systems provide semiconductor manufacturers with the facilities to cover a wide range of device type testing applications.

Deep Sub micron technologies down to 0.13 μ CMOS as well as high voltage BiCMOS technologies are accommodated. High power consumption and high power signal switching, which are needed for the automotive market, are no longer a problem. Also it is possible to use high-speed low voltage digital signals as required by the telecom and audio consumer market with long signal pattern depths.



MIDAS© 4500 system

Advanced Burn-In & Reliability Testing Technology

Reltech

The unique MIDAS© (Micro Processor Data Acquisition) system... meeting the testing challenge of multi function semiconductor devices

◆ MIDAS© - a conceptual approach to performing advanced and automated dynamic Burn-In and Reliability testing of Logic, Microprocessor, Mixed Signal and S.O.C (System on Chip) devices.

◆ MIDAS© is modular - key functions (e.g. Pattern Generation, SRAM, Output drivers, PC104) all being performed on separate modules under microprocessor control.

◆ Modular flexibility provides easy upgrading for new or different devices to be accommodated.

◆ MIDAS© provides a standardised and universal hardware and software platform. The MIDAS© Mother board contains functional modules, which can be easily changed, enabling fast and effective configuration for testing different device technologies.

◆ Digital and Analogue high speed stimulation for the latest S.O.C (system on chip) devices

◆ High speed and low voltage test patterns

◆ Dynamic Allocation of RAM allowing width x depth test pattern configuration

◆ Graphical Waveform Editing via MIDAS© software

◆ System and optional DUT level monitoring

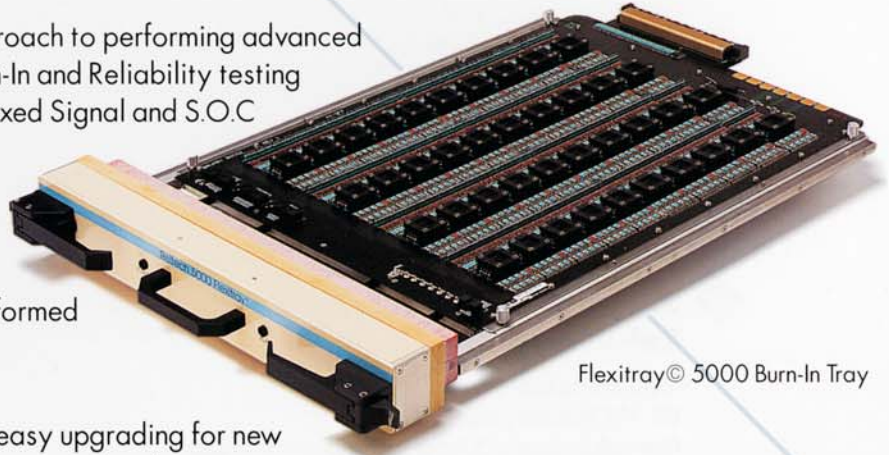
◆ ATE test programme conversion to MIDAS© format

◆ Remote control over networked system using TCIP

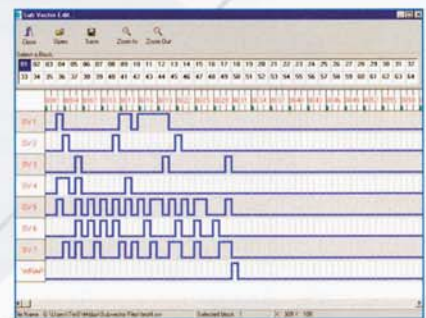
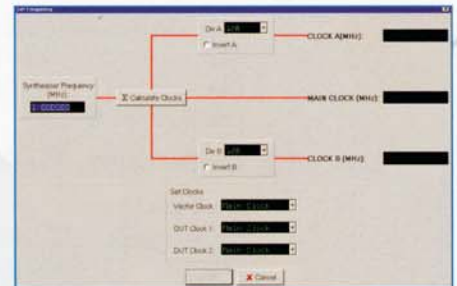
◆ High performance Burn-In Trays

◆ Multi layer designs for high pin count, high speed testing

◆ Burn-in Trays for the latest semiconductor package styles e.g. PQFP, TSOP, BGA, μ BGA and CSP (chip scale package).



Flexitray© 5000 Burn-In Tray



MIDAS© Automated System Programming and Control

Reltech Limited... total capability in advanced logic and mixed signal semiconductor Burn-In Test technology

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